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PUBLICATION FONDAMENTALE EN CEM

**Specification for radio disturbance and immunity measuring apparatus and methods –
Part 1-2: Radio disturbance and immunity measuring apparatus – Coupling devices for conducted disturbance measurements**

**Spécifications des méthodes et des appareils de mesure des perturbations radioélectriques et de l'immunité aux perturbations radioélectriques –
Partie 1-2: Appareils de mesure des perturbations radioélectriques et de l'immunité aux perturbations radioélectriques – Dispositifs de couplage pour la mesure des perturbations conduites**



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INTERNATIONAL ELECTROTECHNICAL COMMISSION
INTERNATIONAL SPECIAL COMMITTEE ON RADIO INTERFERENCE

**SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY
MEASURING APPARATUS AND METHODS –**

**Part 1-2: Radio disturbance and immunity measuring apparatus –
Coupling devices for conducted disturbance measurements**

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International Standard CISPR 16-1-2 has been prepared by subcommittee A: Radio-interference measurements and statistical methods, of IEC technical committee CISPR: International special committee on radio interference.

This second edition cancels and replaces the first edition published in 2003 and its Amendment 1 (2004) and Amendment 2 (2006). This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) requirements from CISPR 22 for the AAN have been copied to this standard;
- b) the CDNE for measurement of disturbance voltage in the frequency range 30 MHz to 300 MHz is added;
- c) additional maintenance is included.

It has the status of a basic EMC publication in accordance with IEC Guide 107, *Electromagnetic compatibility – Guide to the drafting of electromagnetic compatibility publications*.

The text of this standard is based on the following documents:

FDIS	Report on voting
CISPR/A/1051/FDIS	CISPR/A/1059/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

A list of all parts of CISPR 16 series, under the general title *Specification for radio disturbance and immunity measuring apparatus and methods*, can be found on the IEC website.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

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SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY MEASURING APPARATUS AND METHODS –

Part 1-2: Radio disturbance and immunity measuring apparatus – Coupling devices for conducted disturbance measurements

1 Scope

This part of the CISPR 16 series specifies the characteristics and performance of equipment for the measurement of radio disturbance voltages and currents in the frequency range 9 kHz to 1 GHz.

NOTE In accordance with IEC Guide 107, CISPR 16 is a basic EMC standard for use by product committees of the IEC. As stated in Guide 107, product committees are responsible for determining the applicability of the EMC standard. CISPR and its sub-committees are prepared to co-operate with product committees in the evaluation of the value of particular EMC tests for specific products.

Specifications for ancillary apparatus are included for artificial mains networks, current and voltage probes and coupling units for current injection on cables.

It is intended that the requirements of this publication are fulfilled at all frequencies and for all levels of radio disturbance voltages and currents within the CISPR indicating range of the measuring equipment.

Methods of measurement are covered in the CISPR 16-2 series, and further information on radio disturbance is given in CISPR 16-3, while uncertainties, statistics and limit modelling are covered in the CISPR 16-4 series.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

CISPR 16-1-1:2010, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-1: Radio disturbance and immunity measuring apparatus – Measuring apparatus*

CISPR 16-2-1:2014, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 2-1: Methods of measurement of disturbances and immunity – Conducted disturbance measurements*

CISPR 16-4-2:2011, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 4-2: Uncertainties, statistics and limit modelling – Measurement instrumentation uncertainty*

IEC 60050 (all parts), *International Electrotechnical Vocabulary* (available at <http://www.electropedia.org>)

IEC 61000-4-6:2008, *Electromagnetic compatibility (EMC) – Part 4-6: Testing and measurement techniques – Immunity to conducted disturbances, induced by radio-frequency fields*